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FCPF1300N80Z

N-Channel SuperFET[®] II MOSFET

800 V, 6 A, 1.3 Ω

Features

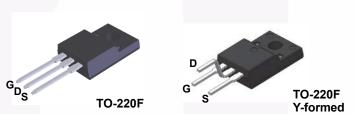
- R_{DS(on)} = 1.05 Ω (Typ.)
- Ultra Low Gate Charge (Typ. Q_g = 16.2 nC)
- Low E_{oss} (Typ. 1.57 uJ @ 400V)
- Low Effective Output Capacitance (Typ. C_{oss(eff.)} = 48.7 pF)
- 100% Avalanche Tested
- RoHS Compliant
- ESD Improved Capability

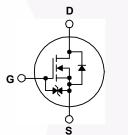
Applications

- AC DC Power Supply
- LED Lighting

Description

SuperFET[®] II MOSFET is Fairchild Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This technology is tailored to minimize conduction loss, provide superior switching performance, dv/dt rate and higher avalanche energy. In addition, internal gate-source ESD diode allows to withstand over 2kV HBM surge stress. Consequently, SuperFET II MOSFET is very suitable for the switching power applications such as Audio, Laptop adapter, Lighting, ATX power and industrial power applications.





Absolute Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol	Parameter			FCPF1300N80Z FCPF1300N80ZYD	Unit	
V _{DSS}	Drain to Source Voltage			800	V	
N/	Cata to Source Valtage	- DC		±20	V	
V _{GSS}	Gate to Source Voltage	- AC	(f > 1 Hz)	±30	v	
I _D	Drain Current	- Continuous (T _C = 25 ^o C)		6.0*	Α	
		- Continuous (T _C = 100 ^o C)		3.8*	~	
I _{DM}	Drain Current	- Pulsed	(Note 1)	12*	А	
E _{AS}	Single Pulsed Avalanche Energy (Note 2)			48	mJ	
I _{AR}	Avalanche Current (Note 1)		0.8	Α		
E _{AR}	Repetitive Avalanche Energy		(Note 1)	0.26	mJ	
dv/dt	MOSFET dv/dt			100	V/ns	
	Peak Diode Recovery dv/dt (Note 3)			20		
P _D	Dawar Dissingtion	(T _C = 25 ^o C)		24	W	
	Power Dissipation	- Derate Above 25°C		0.19	W/ºC	
T _J , T _{STG}	Operating and Storage Tempe	rature Range		-55 to +150	°C	
T ₁	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds		300	°C		

Thermal Characteristics

Symbol	Parameter	FCPF1300N80Z FCPF1300N80ZYD	Unit			
$R_{ extsf{ heta}JC}$	Thermal Resistance, Junction to Case, Max.	5.2	°C/W			
R_{\thetaJA}	Thermal Resistance, Junction to Ambient, Max.	62.5				

FCPF130
1300N80Z — 1
N-Channel S
SuperFET®
[®] II MOSFET

FCPF1300N80Z FCPF1300N80Z FCPF1300N80Z Iracteristics T _C = Parameter CS to Source Breakdown Vo down Voltage Temperatu cient Bate Voltage Drain Currer o Body Leakage Current CS Threshold Voltage Drain to Source On Res rd Transconductance teristics Capacitance t Capacitance	25°C un 25°C un obltage ire t	$V_{GS} =$ $I_D = 1$ $V_{DS} =$ $V_{GS} =$ $V_{GS} =$ $V_{GS} =$	TubeTubeTubeTubeTest Conditions0 V, $I_D = 1$ mA, $T_J =$ mA, Referenced to 2800 V, $V_{GS} = 0$ V640 V, $V_{GS} = 0$ V640 V, $V_{GS} = 0$ V20 V, $V_{DS} = 0$ VVDS, $I_D = 0.4$ mA10 V, $I_D = 2$ A20 V, $I_D = 2$ A	5°C		N/A N/A Typ. - 0.85 - - - - 1.05		50 units 50 units Unit V/°C - μΑ μΑ V V/°C
Parameter Parameter CS to Source Breakdown Vo down Voltage Temperatu- cient Sate Voltage Drain Currer o Body Leakage Current CS Threshold Voltage Drain to Source On Res rd Transconductance teristics Capacitance	25°C un 25°C un oltage ure t	$V_{GS} = I_D = 1$ $V_{GS} = V_{DS} = V_{GS} = $	rerwise noted. Test Conditions 0 V, I _D = 1 mA, T _J = mA, Referenced to 2 800 V, V _{GS} = 0 V 640 V, V _{GS} = 0 V,T _C ± 20 V, V _{DS} = 0 V V _{DS} , I _D = 0.4 mA 10 V, I _D = 2 A	25°C 5°C	Min. 800 - - - 2.5	Typ. - 0.85 - - - 1.05	Max. - - 25 250 ±10 4.5	Unit V V/°C μΑ μΑ V
Parameter CS to Source Breakdown Vo down Voltage Temperatu cient Gate Voltage Drain Currer o Body Leakage Curren CS Threshold Voltage Drain to Source On Res rd Transconductance teristics Capacitance	bltage ire ent	$V_{GS} =$ $I_D = 1$ $V_{DS} =$ $V_{GS} =$ $V_{GS} =$ $V_{GS} =$	Test Conditions 0 V, $I_D = 1 \text{ mA}, T_J =$ mA, Referenced to 2 800 V, $V_{GS} = 0 \text{ V}$ 640 V, $V_{GS} = 0 \text{ V}, T_C$ ±20 V, $V_{DS} = 0 \text{ V}$ V _{DS} , $I_D = 0.4 \text{ mA}$ 10 V, $I_D = 2 \text{ A}$	5°C	800 - - - 2.5	- 0.85 - - - - 1.05	- - 25 250 ±10 4.5	V V/ ^o C μΑ μΑ V
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down Voltage Temperatu cient Gate Voltage Drain Curren o Body Leakage Curren CS Fhreshold Voltage Drain to Source On Res rd Transconductance teristics Capacitance	ent	$I_{D} = 1$ $V_{DS} =$ $V_{GS} =$ $V_{GS} =$ $V_{GS} =$	mA, Referenced to 2 800 V, $V_{GS} = 0 V$ 640 V, $V_{GS} = 0 V,T_C$ ±20 V, $V_{DS} = 0 V$ V_{DS} , $I_D = 0.4$ mA 10 V, $I_D = 2$ A	5°C	- - 2.5	- - - 1.05	25 250 ±10 4.5	μΑ μΑ V
Gate Voltage Drain Curren o Body Leakage Curren CS Fhreshold Voltage Drain to Source On Res rd Transconductance teristics Capacitance	t	V _{GS} = V _{GS} = V _{GS} =	640 V, $V_{GS} = 0 V, T_C$ ±20 V, $V_{DS} = 0 V$ V _{DS} , $I_D = 0.4 \text{ mA}$ 10 V, $I_D = 2 \text{ A}$	= 125°C	- - 2.5	- - 1.05	250 ±10 4.5	μA V
o Body Leakage Current cs Threshold Voltage Drain to Source On Res rd Transconductance teristics Capacitance	t	V _{GS} = V _{GS} = V _{GS} =	640 V, $V_{GS} = 0 V, T_C$ ±20 V, $V_{DS} = 0 V$ V _{DS} , $I_D = 0.4 \text{ mA}$ 10 V, $I_D = 2 \text{ A}$	= 125°C	- 2.5	- - 1.05	250 ±10 4.5	μA V
cs Threshold Voltage Drain to Source On Res rd Transconductance teristics Capacitance		V _{GS} = V _{GS} = V _{GS} =	$\pm 20 \text{ V}, \text{ V}_{\text{DS}} = 0 \text{ V}$ V _{DS} . I _D = 0.4 mA 10 V, I _D = 2 A		- 2.5	- 1.05	±10 4.5	V
Threshold Voltage Drain to Source On Res rd Transconductance teristics Capacitance	istance	V _{GS} = V _{GS} =	V _{DS} , I _D = 0.4 mA 10 V, I _D = 2 A					
Threshold Voltage Drain to Source On Res rd Transconductance teristics Capacitance	istance	V _{GS} =	10 V, I _D = 2 A					
Drain to Source On Res rd Transconductance teristics Capacitance	istance	V _{GS} =	10 V, I _D = 2 A					
rd Transconductance teristics Capacitance		00	-		-			
Capacitance		00	, D			4.5	-	S
Capacitance				I		_		
	-				_	661	880	pF
Output Capacitance Reverse Transfer Capacitance			100 V, V _{GS} = 0 V,	-	-	22.3	30	pF
		f = 1 N	ЛНz	_	-	0.74	-	pF
t Capacitance	_	V _D e =	480 V, V _{GS} = 0 V, f =	: 1 MHz	-	11.4	-	pF
ve Output Capacitance	-				-	48.7	-	pF
Sate Charge at 10V	_				-	16.2	21	nC
o Source Gate Charge				-	-	3.5	-	nC
o Drain "Miller" Charge				(Note 4)	-	6.8	-	nC
alent Series Resistance		f = 1 N	ЛНz		-	4	-	Ω
cteristics								
					- /	14	38	ns
,		V _{DD} =	400 V, I _D = 4 A,	-		8.3	27	ns
				-	-	33	76	ns
				(Note 4)	-	6	22	ns
-0 -0 -0	Gate Charge at 10V to Source Gate Charge to Drain "Miller" Charge valent Series Resistance acteristics -On Delay Time -On Rise Time -Off Delay Time -Off Fall Time	Gate Charge at 10V to Source Gate Charge to Drain "Miller" Charge valent Series Resistance acteristics -On Delay Time -On Rise Time -Off Delay Time	Gate Charge at 10V V_{DS} =to Source Gate Charge V_{GS} =to Drain "Miller" Charge V_{GS} =valent Series Resistance $f = 1 \text{ M}$ acteristics-On Delay Time V_{DD} =-On Rise Time V_{GS} =-Off Delay Time V_{GS} =-Off Fall Time V_{GS} =	Gate Charge at 10V $V_{DS} = 640 \text{ V}, \text{ I}_D = 4 \text{ A},$ $V_{GS} = 10 \text{ V}$ a to Source Gate Charge $V_{GS} = 10 \text{ V}$ a to Drain "Miller" Charge $r = 1 \text{ MHz}$ valent Series Resistance $f = 1 \text{ MHz}$ acteristics $r = 1 \text{ MHz}$ -On Delay Time $V_{DD} = 400 \text{ V}, \text{ I}_D = 4 \text{ A},$ $V_{GS} = 10 \text{ V}, \text{ R}_g = 4.7 \Omega$ -Off Delay Time $Off Fall Time$	Gate Charge at 10V $V_{DS} = 640 \text{ V}, \text{ I}_D = 4 \text{ A},$ $V_{GS} = 10 \text{ V}$ to Source Gate Charge $V_{GS} = 10 \text{ V}$ to Drain "Miller" Charge(Note 4)valent Series Resistance $f = 1 \text{ MHz}$ racteristicsOn Delay Time -On Rise Time-Off Delay Time $V_{DD} = 400 \text{ V}, \text{ I}_D = 4 \text{ A},$ $V_{GS} = 10 \text{ V}, \text{ R}_g = 4.7 \Omega$ -Off Fall Time(Note 4)	Gate Charge at 10V $V_{DS} = 640 \text{ V}, I_D = 4 \text{ A},$ $V_{GS} = 10 \text{ V}$ -to Source Gate Charge $V_{GS} = 10 \text{ V}$ -to Drain "Miller" Charge(Note 4)-valent Series Resistance $f = 1 \text{ MHz}$ -acteristics-On Delay Time-On Rise Time $V_{DD} = 400 \text{ V}, I_D = 4 \text{ A},$ $V_{GS} = 10 \text{ V}, R_g = 4.7 \Omega$ -Off Fall Time(Note 4)-	Gate Charge at 10V $V_{DS} = 640 \text{ V}, I_D = 4 \text{ A},$ $V_{GS} = 10 \text{ V}$ -16.2to Source Gate Charge $V_{GS} = 10 \text{ V}$ -3.5to Drain "Miller" Charge(Note 4)-6.8valent Series Resistancef = 1 MHz-4acteristics-On Delay Time-14-On Rise Time $V_{DD} = 400 \text{ V}, I_D = 4 \text{ A},$ $V_{GS} = 10 \text{ V}, R_g = 4.7 \Omega$ -14-Off Delay Time-33Off Fall Time(Note 4)-6	Gate Charge at 10V $V_{DS} = 640 \text{ V}, I_D = 4 \text{ A}, V_{GS} = 10 \text{ V}$ - 16.2 21 to Source Gate Charge $V_{GS} = 10 \text{ V}$ - 3.5 - to Drain "Miller" Charge (Note 4) - 6.8 - valent Series Resistance f = 1 MHz - 4 - acteristics -On Delay Time - 14 38 -On Rise Time V_{DD} = 400 V, I_D = 4 A, V_{GS} = 10 V, R_g = 4.7 \Omega - 8.3 27 -Off Delay Time - 33 76 -Off Fall Time (Note 4) - 6 22

I _S	Maximum Continuous Drain to Source Diode	-	-	6	А	
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	12	Α
V _{SD}	Drain to Source Diode Forward Voltage V_{G}	_{GS} = 0 V, I _{SD} = 4 A	-	-	1.2	V
t _{rr}	Reverse Recovery Time V _G	_{SS} = 0 V, I _{SD} = 4 A,	-	275	-	ns
Q _{rr}	Reverse Recovery Charge dl _F	₌/dt = 100 A/μs	-	2.9	-	μC

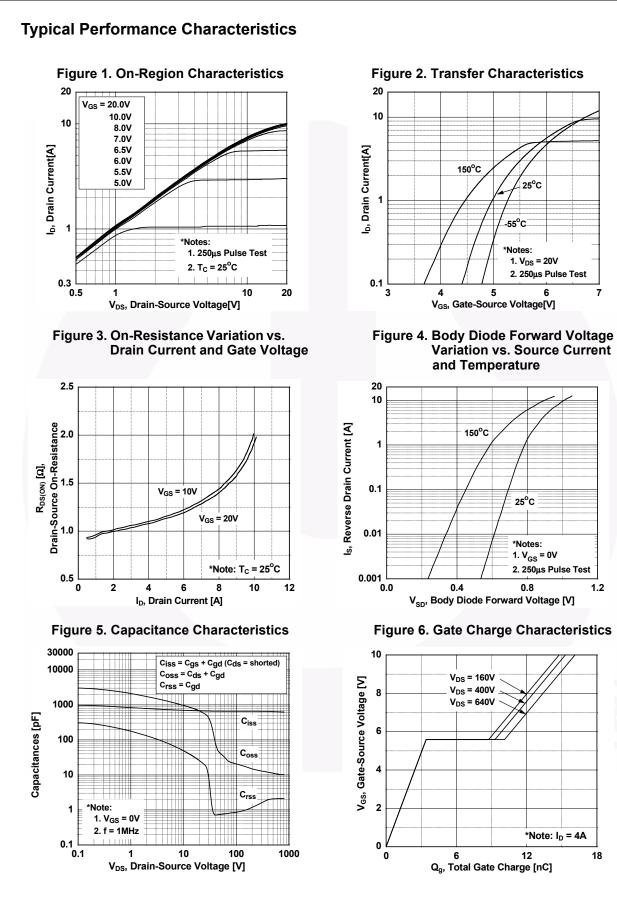
Notes:

1. Repetitive rating: pulse width limited by maximum junction temperature.

2. I_{AS} = 0.8 A, R_G = 25 $\Omega_{\!\!,}$ starting T_J = 25°C

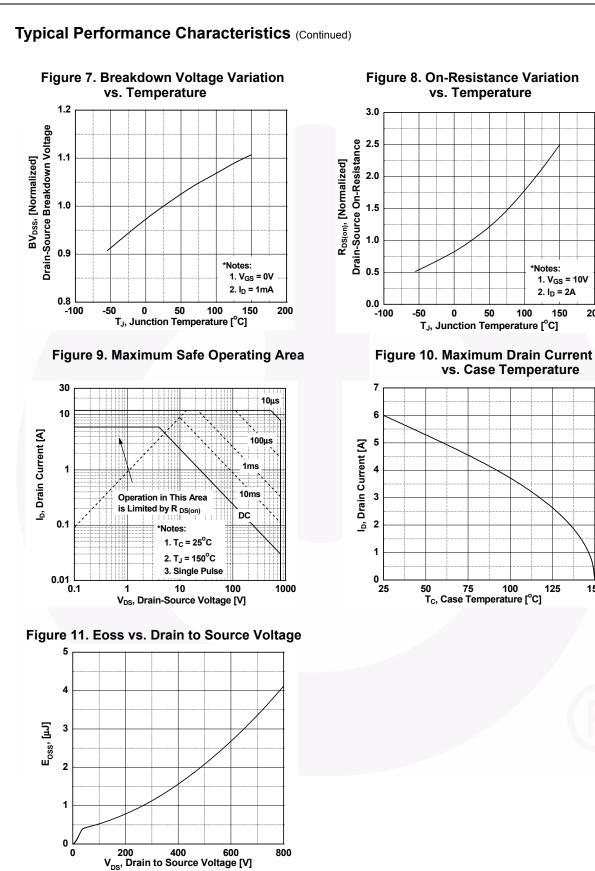
3. I_{SD} \leq 6 A, di/dt \leq 200 A/µs, V_{DD} \leq BV_{DSS}, starting T_J = 25°C

4. Essentially independent of operating temperature typical characteristic.

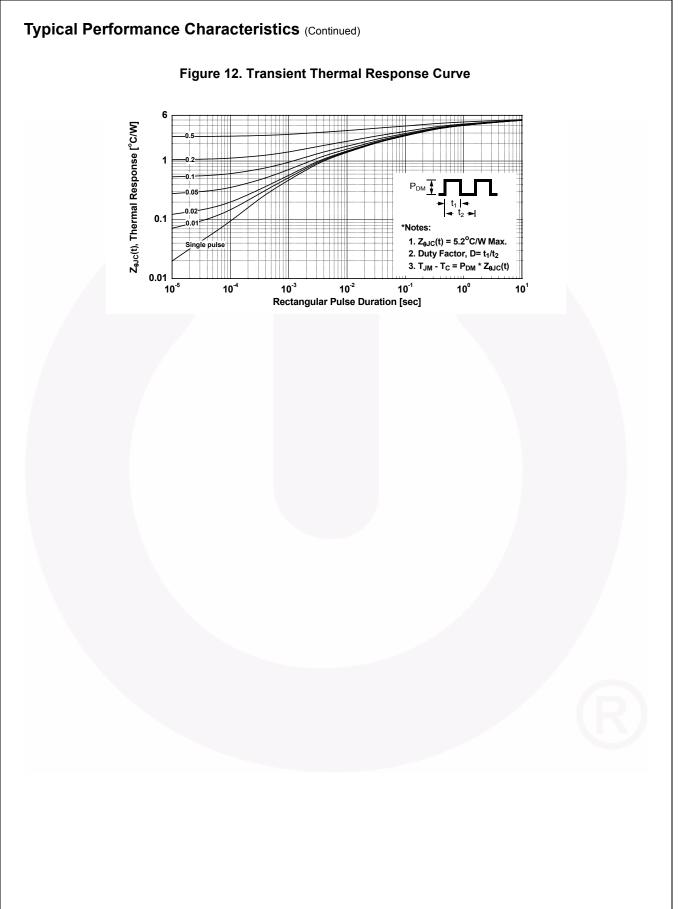


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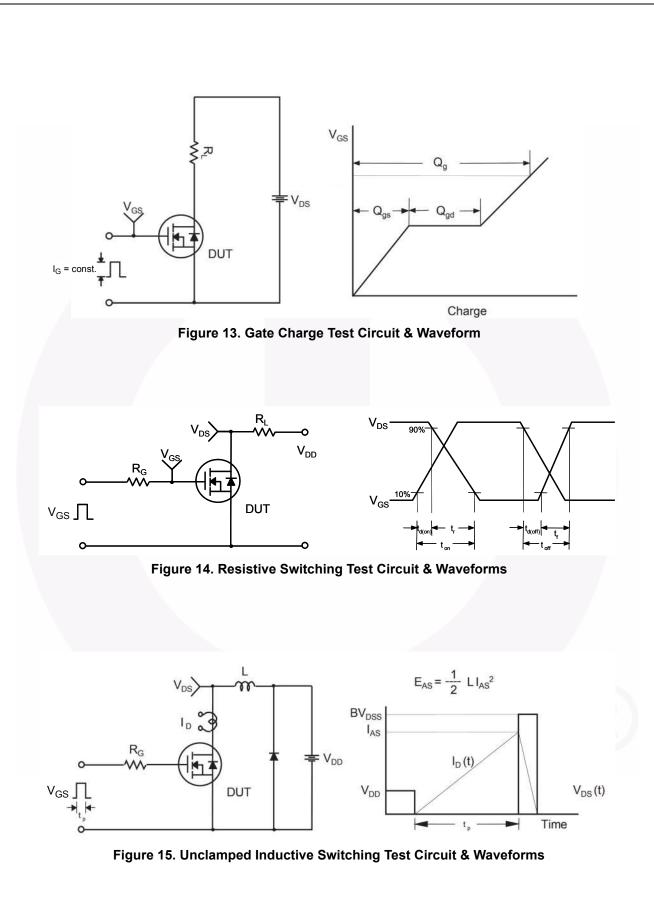




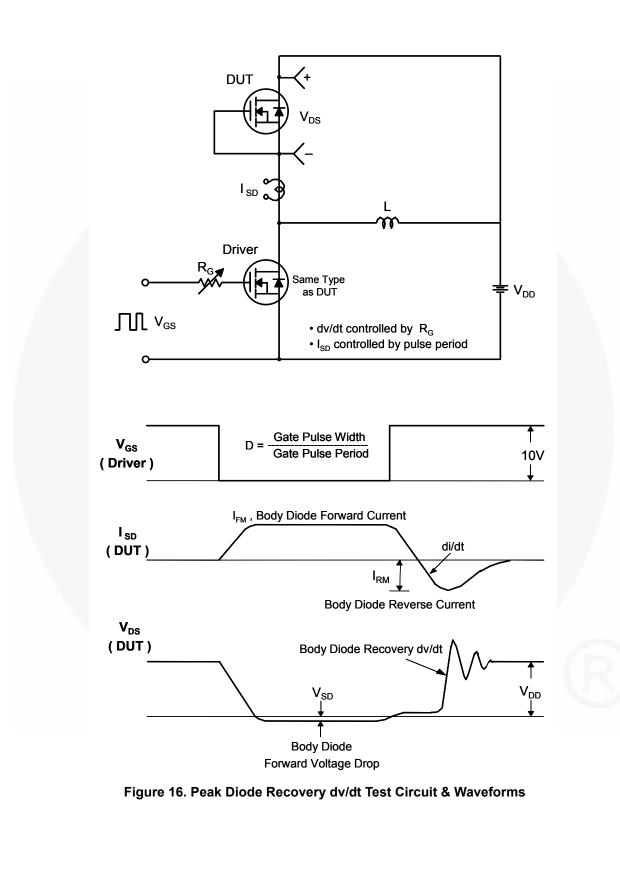
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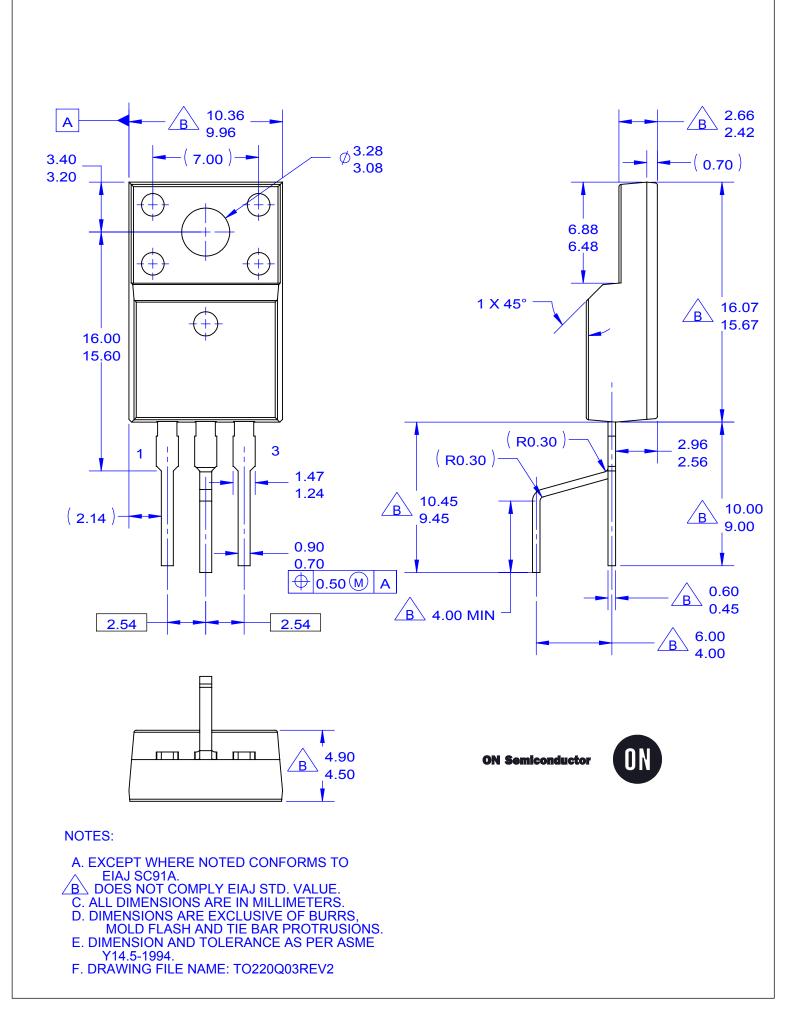


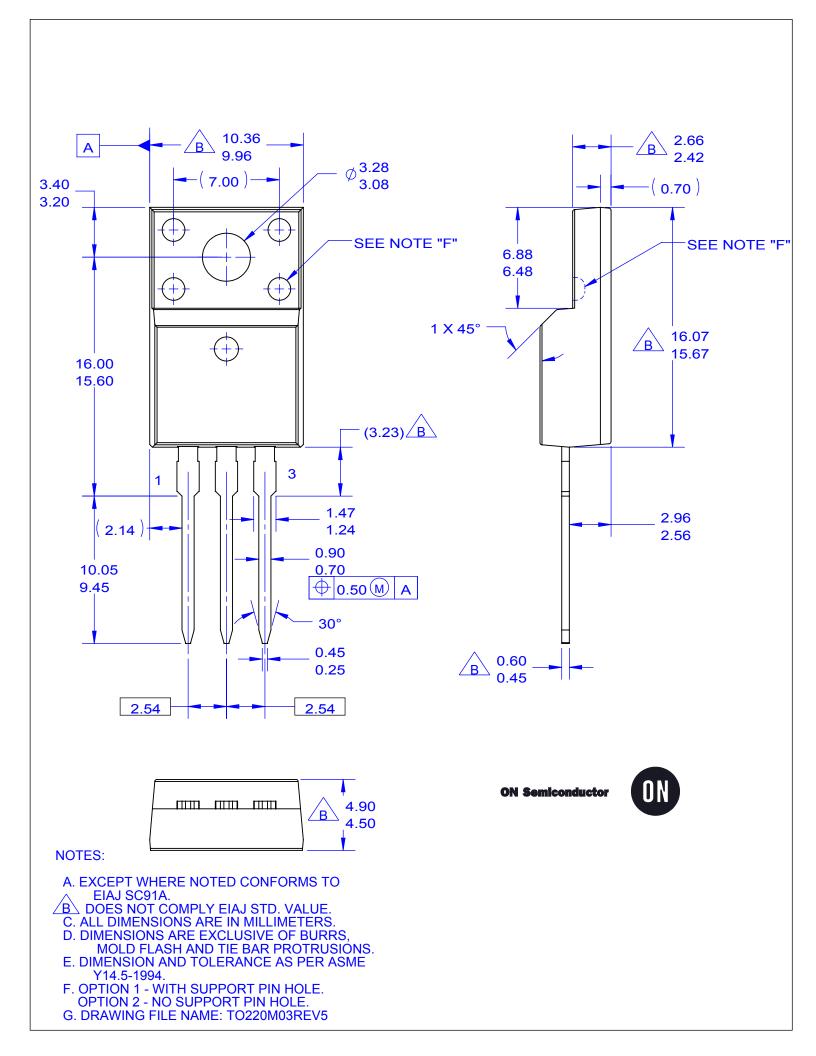
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FCPF1300N80Z — N-Channel SuperFET[®] II MOSFET







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